Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	,
10/774,690	TANAKA ET AL.	
Examiner	Art Unit	
Leith A. Al-Nazer	2821	

SEARCHED				
Class	Subclass	Date	Examiner	
315	111.21- 111.71	1/19/2006	LA	
422	168-183	1/19/2006	LA	
422	186.04	1/19/2006	LA	
422	186.18	1/19/2006	LA	
423	210	1/19/2006	LA	
423	235	1/19/2006	LA	
423	245.1	1/19/2006	3	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
315	111,21-	1/19/06	1a	
422	168 - 183	1/17/06	20	
422	186.04,	1/19/06	20	
423/210, 235, 245.1		1/19/06	20	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated EAST prior art text search (see "Examiner Search Notes")	1/19/2006	LA		
EAST interference text search (see "Examiner Search Notes")	1/19/2006	LA		